

<b>Notice of References Cited</b>	Application/Control No. 09/110,694	Applicant(s)/Patent Under Reexamination MILLS, RANDELL L.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Souw, "Plasma density measurement in an imperfect microwave cavity", Journal of Applied Physics, vol. 61, no. 5, pp. 1761-1772 (3/1987) [attachment 1]
	V	Evans Analytical Group, "Time-Of-Flight Secondary Ion Mass Spectroscopy (TOF-SIMS)" <a href="http://www.cea.com/tech.htm#esca1">http://www.cea.com/tech.htm#esca1</a> (2/1998) [attachment 2]
	W	"XPS (EASC) --- SAM" <a href="http://www.noveoninc.com/measurementScience/analyticalServices/XPSESCASam.pdf">http://www.noveoninc.com/measurementScience/analyticalServices/XPSESCASam.pdf</a> (date unknown) [attachment 3]
	X	"INRS-Energie et Materiaux XPS Facility" <a href="http://goliath.inrs-ener.quebec.ca/tour/">http://goliath.inrs-ener.quebec.ca/tour/</a> (11/2002) [attachment 4]

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	U	Luggenhölscher et al., "Investigations on Electric Field Distributions in a Microwave Discharge in Hydrogen" <a href="http://www.phys.tue.nl/FLTPD/poster/luggenhoelscher.pdf">http://www.phys.tue.nl/FLTPD/poster/luggenhoelscher.pdf</a> (date unknown) [attachment 5]
	V	Mills et al. "Comparison of Excessive Balmer alpha Line Broadening of Inductively and Capacitively Coupled RF, Microwave, and Glow-Discharge Hydrogen Plasmas With Certain Catalysts" IEEE Transactions On Plasma Science, vol. 31, no. 3, pp. 338-355 (6/2003) [attachment 6]
	W	Zona Land "The Physics Department - Mechanics, Curved Motion" <a href="http://id.mind.net/~zona/mstm/physics/mechanics/curvedMotion/curvedMotion.html">http://id.mind.net/~zona/mstm/physics/mechanics/curvedMotion/curvedMotion.html</a> (10/2001)
	X	Zona Land "Non-inertial Frame of Reference" <a href="http://id.mind.net/~zona/mstm/physics/mechanics/framesOfReference/nonInertialFrame.html">http://id.mind.net/~zona/mstm/physics/mechanics/framesOfReference/nonInertialFrame.html</a> (10/2001)

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